

## Characterization of irradiated SiPM for the TOP detector at the Belle II experiment

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### Ezio Torassa, Roberto Stroili, Jakub Kandra INFN Padova

### **Content**



- Irradiated SiPM modules in Padova
- Studies of current-voltage characteristics for SiPMs depending on:
	- Working temperature
	- Level of irradiation
	- Producers
- Software tools to read waveforms
- Background subtraction and extracting signal
- Preliminary photon spectra studies
- **Conclusion**

## Tests with irradiated modules in Padova



- In Belle II, MCP-PMTs with extended lifetime have been installed and they have limited lifetime depending on accumulated charge.
- We are trying to understand if they eventually can be replaced with SiPMs.
- We irradiated 24 SiPMs modules with different neutron fluxes and tested by laser.
- Eight of them are processed to study their response.
- Collected data are read from modules and analyzed.



### Current-voltage characteristic of some SiPM at +20<sup>∘</sup>C



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- Running at room working temperature, it does not change breakdown voltages much.
	- Non-irradiated FBKs ∼ 33 V and Hamamatsu ∼ 38 V
	- Irradiated FBKs ∼ 33 V (mostly same for all) and Hamamatsu ∼ 38 V
- Current-voltage characteristic rapidly change if FBKs are irradiated or not.
- Non-irradiated FBKs have  $1F+05$  $\tilde{E}$ shape of characteristic similar, but Hamamatsu has different  $1F+04$ to FBKs
- High irradiated shapes of FBKs and Hamamatsu are very similar, their tails depends on level of irradiation.
- Less irradiated  $14<sup>th</sup>$  SiPM is closer to non-irradiated shape



### Current-voltage characteristic of some SiPM at -10<sup>∘</sup>C



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- Decreasing temperature, breakdown voltages are still similar before and after irradiation
	- Non-irradiated FBKs ∼ 33 V and Hamamatsu ∼ 38 V
	- Irradiated FBKs ∼ 33 V (mostly same for all) and Hamamatsu ∼ 38 V
- Current-voltage characteristic rapidly change if FBKs are irradiated or not, but they are closer
- Non-irradiated FBKs have shape of characteristic similar, but Hamamatsu has different to FBKs
- High irradiated shapes of FBKs and Hamamatsu are very similar, their tails depends on level of irradiation.
- Less irradiated  $14<sup>th</sup>$  SiPM is closer to non-irradiated shape



### Current-voltage characteristic of some SiPM at -30<sup>∘</sup>C



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- At low temperature, FBK and Hamamatsu SiPMs have different breakdown voltages:
	- Non-irradiated FBKs ∼ from 38 to 42 V and Hamamatsu ∼ 38 V
	- Irradiated FBKs ∼ 30 V (all very close to each other) and Hamamatsu ∼ 35 V
- Current-voltage characteristic rapidly change if SiPMs are irradiated highly or not.
- Non-irradiated FBKs have  $1F+05$  $\approx$ shape of characteristic similar, but Hamamatsu has different  $1F+04$ to FBKs
- Irradiated shapes of FBKs are  $_{1E+03}$ fully dependent level of irradiation and dimension, but  $1F+02$ Hamamatsu is closer to non-irradiated curve in  $1E+01$ comparison with  $12<sup>th</sup>$  SiPM (same level of irradiation)



### Current-voltage characteristic for FBK 8<sup>th</sup> SiPM



- Decreasing working temperature, breakdown points are changing a lot:
	- Non-irradiated breakdown points are between 32 to 42 V (it depends on definition)
	- Irradiated breakdown points are between 31 to 33 V
- Huge difference between irradiated and non-irradiated characteristics for high irradiated SiPM
- Non-irradiated characteristics shapes are changing as function of temperature
- Irradiated characteristics are not changing too much in comparison to non-irradiated working temperatures.



### Current-voltage characteristic for FBK 14<sup>th</sup> SiPM



- Decreasing working temperature, breakdown points are changing a lot:
	- Non-irradiated breakdown points are between 32 to 44 V (it depends on definition)
	- Irradiated breakdown points are between 32 to 34 V
- Small difference between irradiated and non-irradiated characteristics for low irradiated SiPM
- Non-irradiated characteristics shapes are changing as function of temperature
- Irradiated characteristics are changing more in comparison to high irradiated SiPM (similar to non-irradiated working temperatures).



### Current-voltage characteristic for Hamamatsu SiPM (15th)



- Decreasing working temperature, breakdown points does not change much
	- Non-irradiated breakdown points are between 36 to 38 V
	- Irradiated breakdown points are between 35 to 37 V
- At high temperatures characteristics are more similar, at low temperatures there is difference
- Non-irradiated characteristics shapes are changing as function of temperature
- Irradiated characteristics are not changing too much in comparison to non-irradiated working temperatures.



### **Content**



- Irradiated SiPM modules in Padova
- Studies of current-voltage characteristics for SiPMs depending on:
	- Working temperature
	- Level of irradiation
	- Producers
- Experimental setup and software tools for our tests
- Background subtraction and extracting signal
- Preliminary photon spectra studies
- **Conclusion**

## Experimental setup and software tools



- SiPM devices were illuminated with a laser beam with 20 ps time resolution attenuating the beam in order to work with a small number of photons, because in the detector we will have to detect only single photons.
- For data processing, we are using **TSpectrum Class in ROOT environment**
- Peaks are found using [SearchHighRes](https://root.cern.ch/doc/master/classTSpectrum.html#a5ba181a45b117934b48c4ef5f78d0b2b) function based on
	- Subtraction background using deconvolution
	- deconvolution<br>
	 Allowing smoothing extracted spectrum<br>
	using Markov algorithm<br>
	 Returns using Markov algorithm
	- Returns
		- Number of founded peaks
		- Extracted spectrum



## Background subtraction and extracting signal

- In [TSpectrum Class](https://root.cern.ch/doc/master/classTSpectrum.html) in ROOT environment, there is another [Background](https://root.cern.ch/doc/master/classTSpectrum.html#a56e15d1c36c7557b17d5f6d68fa315a7) function to simply estimate background
- It allows to extract signal spectra by two different methods:
	- As output of [SearchHighRes](https://root.cern.ch/doc/master/classTSpectrum.html#a56e15d1c36c7557b17d5f6d68fa315a7) function
	- $\circ$  As difference between original waveform  $\frac{2}{3}$ and output of **[Background](https://root.cern.ch/doc/master/classTSpectrum.html#a56e15d1c36c7557b17d5f6d68fa315a7)** function
- Difference between original waveform and output of **Background** function can be smoothed by Markov algorithm using [SmoothMarkov](https://root.cern.ch/doc/master/classTSpectrum.html#a2767b767d39ee7826e9a50b9c0359beb) function
- Jakub Kandra, INFN Padova  $\bullet$  Both methods are compared  $\bullet$  12







## Waveform spectrum for 14<sup>th</sup> SiPM



Background is determined averaging original waveform in several iterations



#### Jakub Kandra, INFN Padova

### Other options for waveform spectrum for 14<sup>th</sup> SiPM

- As was shown at slide 6:
	- Higher number background iterations increase peak amplitudes
	- Allowing smoothing using Markov algorithm, peak amplitude rises
- There is another possibilities how to model peak shapes:
	- Increasing smoothing iterations amplitude of peaks grows
	- Wider signal peaks can be found using increasing sigma of founded peaks





### Fit of photon spectra



1400

1400

#### SiPM #13 700 events Number of events600 500 Number of 300  $200$  $400$ 600 200 Residual of Histogram of ds1 plot x and Projection of dmodel 60 40 Residual<br>- 20<br>20<br>20  $20$ ---  $-40$  $-60$ 200 400 600 800 1000 1200 Pull of Histogram of ds1 plot x and Projection of dmodel Pulls ----

400

- Photon spectra are extracted
- Photon spectra are fitted sum of convolution poissonian and gaussian distribution to extract gain and average of photons
- From gain we can extract breakdown voltage

 $\Omega$ 

200



16

### Extraction of breakdown voltage from spectra



### Gain as function of overvoltage



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- Extracted breakdown voltage can be subtracted from bias voltage
- Irradiated and non-irradiated results are consistent, but we see some inconsistencies at 0 <sup>∘</sup>C, we plan to investigate a source.

**SiPM #13** 32 Non-irradiated at 20° Non-irradiated at -20°  $\circ$  $\circ$ 30 Irradiated at 20° Irradiated at -20° Non-irradiated at 10° Non-irradiated at -30°  $\circ$  $\circ$ 28 Irradiated at 10° Irradiated at -30° Gain [mV] 26 Non-irradiated at 0° Non-irradiated at -35°  $\circ$  $\circ$ Irradiated at 0° Irradiated at -35° 24 Non-irradiated at -10° Non-irradiated at -40°  $\circ$  $\circ$ 22 Irradiated at -10° Irradiated at -40° 20 18  $\mathbf 0$  $\overline{2}$ 6 8  $V_{bias} - V_0$  [V] **SiPM #15** 40 Non-irradiated at 20° Non-irradiated at -20°  $\circ$  $\circ$ 35 Irradiated at 20° Irradiated at -20° Non-irradiated at 10° Non-irradiated at -30°  $\circ$ 30 Irradiated at 10° Irradiated at -30° Gain [mV] Non-irradiated at 0° Non-irradiated at -35°  $\circ$  $\circ$ 25 Irradiated at 0° Irradiated at -35° Non-irradiated at -10° Non-irradiated at -40°  $\circ$ 20 Irradiated at -10° Irradiated at -40° 15 10  $-2$  $\Omega$ 6  $-4$  $V_{bias} - V_0$  [V]

### Breakdown voltages at temperatures for SiPMs





• For Hamamatsu device the breakdown voltages agree with previous measurements

• For some FBK devices, the breakdown voltages do not agree with previous measurements.

• After finishing studies related to breakdown voltage, we will continue with extraction time resolution

## **Conclusion**



- In Padova it has been irradiated and tested several SiPM modules
- Current-voltage characteristics have been analyzed
	- As function of level of irradiation
	- Working temperature
	- Different producers
- Characteristics are changing in function of irradiation and working temperatures, but it highly depends on the producers
- For some of them data has been processed and analyzed in **[TSpectrum Class](https://root.cern.ch/doc/master/classTSpectrum.html)** in ROOT environment, where we can
	- Suppress background
	- Smooth and deconvolute spectrum
	- Search for peaks
- Data has been processed to provide photon spectra and it was fitted to extract gain and average of photons.
- From gain we extract breakdown voltage and compare between irradiated and non-irradiated cases.
- We plan study average of photons and time resolution in next weeks.
- These devices will be irradiated again to reach higher doses and currently they are in annealing process at 150 <sup>∘</sup>C



# Backup



## SiMP #14

#### Time resolution and photon spectrum for 14<sup>th</sup> SiPM  $\left\langle \right\rangle$ **INFN**



### Time resolution and photon spectrum for 14<sup>th</sup> SiPM  $\left\langle \right\rangle$



**INFN** 



## SiMP #13

### Time resolution and photon spectrum for 13<sup>th</sup> SiPM  $\left\{ \frac{1}{2} \right\}$ **INFN**



### Time resolution and photon spectrum for 13<sup>th</sup> SiPM  $\left\{ \frac{1}{2} \right\}$ **INFN**





## SiMP #12

### Time resolution and photon spectrum for 12<sup>th</sup> SiPM  $\left\langle \right\rangle$ **INFN**



### Time resolution and photon spectrum for 12<sup>th</sup> SiPM  $\left\langle \right\rangle$ INFŃ





## SiMP #11

### Time resolution and photon spectrum for 11<sup>th</sup> SiPM  $\left\langle \right\rangle$ INFŃ



### Time resolution and photon spectrum for 11<sup>th</sup> SiPM  $\left\{ \mathcal{B}_{n}\right\}$ INFŃ





## SiMP #15

### Time resolution and photon spectrum for 15<sup>th</sup> SiPM  $\left\{ \mathcal{B}_{n}\right\}$ INFŃ



### Time resolution and photon spectrum for 15<sup>th</sup> SiPM  $\left\{ \mathcal{B}_{n}\right\}$ INFŃ



### Time resolution and photon spectrum for 15<sup>th</sup> SiPM  $\left\{ \mathcal{B}_{n}\right\}$ INFŃ



## Background level and expected neutron flux



- For MCP-PMT the most crucial background is degradation of quantum efficiency
- Instead for SiPM the most critical is neutron flux, because increase count rate
- Study of neutron flux is part of background studies at LS2, which is ongoing
- Current study (based on 19<sup>th</sup> Monte Carlo Campaign) report about neutron flux at TOP at level of 2.5  $\cdot$ 10<sup>10</sup> neutrons/cm<sup>2</sup>/year (with luminosity 8 $\cdot$ 10<sup>35</sup> cm<sup>-2</sup> s<sup>-1</sup>)
- Now expected luminosity at LS2 is 6.0∙10<sup>35</sup> cm<sup>-2</sup> s<sup>-1</sup>



## First result on irradiated SiPM Hamamatsu



- In winter 2022, 8 Hamamatsu 1.3x1.3 mm<sup>2</sup> x 50 µm cells (S13360-1350PE) SiPMs were measured in Padova
- SiPMs were irradiated at different distances from target and different integration times
- $\bullet$  SiPMs was irradiated with fluences in range from 1⋅10<sup>9</sup> to 5⋅10<sup>11</sup> neutrons cm<sup>2</sup>
- Increase of dark counting due to neutron irradiation can be partially compensated by operating SiPMs at low temperature, damages produced by  $\frac{1}{2}$ neutron irradiation can be partially recovered with annealing process









## First result on irradiated SiPM Hamamatsu



- In winter 2022, 8 Hamamatsu 1.3x1.3 mm<sup>2</sup> x 50 µm cells (S13360-1350PE) SiPMs was measured in Padova
- SiPMs was irradiated at different distances from target and different integration times
- SiPMs was irradiated with fluences in range from 1 $\cdot$ 10<sup>9</sup> to 5 $\cdot$ 10<sup>11</sup>
- Damage could be partially recovered by operating SiPMs at low temperature





## Further plans with SiPM

- In Summer 2023 next irradiated test will be done:
	- $\circ$  3 FBK 3x3 mm<sup>2</sup> x 15 µm cells (FBK-NUV-HD-RH-3015)
	- $\circ$  4 FBK 1x1 mm<sup>2</sup> x 15 µm cells (FBK-NUV-HD-RH-1015)
	- o 1 Hamamatsu 3x3 mm<sup>2</sup> x 50 μm cells (S14160-3050HS)
- Irradiation measurement based on 16 SiPMs.
- The maximum fluence is planned 1∙10<sup>11</sup>
- The goal is identify the cell size giving better radiation hardness performance (lower cell size is expected to be better).
- Try to recover from irradiation to heat SiPMs around 150 °C for 3 weeks
- After Summer 2023 irradiation tests, a new SiPM prototype will be developed with FBK, the production of masks will take 6 months and cost 50 keurs financed with AIDAinnova (EU project).
- The goal is the further improvements the low field technology (regions with high field increase the count rate)



